





an Open Access Journal by MDPI

Advances in AI Technology for Remote Sensing Image Processing

Guest Editors:

Message from the Guest Editors

Dr. Yanlong Guo

Dear Colleagues,

Dr. Wenfei Luan

Dr. Zehin Zhao

Deadline for manuscript submissions:

15 February 2025

This Special Issue highlights pioneering research that leverages advanced AI techniques—including deep learning, reinforcement learning, transfer learning, and long short-term memory (LSTM) networks—to transform the processing and analysis of remote sensing data. Emphasis is placed on the application of cutting-edge methods, such as causal analysis and physics-informed machine learning, in remote sensing. Additionally, the Special Issue will explore the development and advancements in knowledge graphs and large-scale foundational models, which are pivotal in enhancing the accuracy and interpretability of remote sensing analyses. These innovations are propelling the automation of remote sensing workflows, enabling efficient and scalable solutions. The Special Issue will also address critical technical challenges in making remote sensing data Al-READY, focusing on improving data quality, enhancing model interpretability, and optimizing computational efficiency. This Special Issue aims to provide a comprehensive overview of how AI is revolutionizing remote sensing, paving the way for more intelligent, automated, and reliable data processing solutions.











an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and Telecommunications, Politecnico di Torino, 10129 Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with article processing charges (APC) paid by authors or their institutions.

High Visibility: indexed within Scopus, SCIE (Web of Science), CAPlus / SciFinder, Inspec, Ei Compendex and other databases.

Journal Rank: JCR - Q2 (Physics, Applied) / CiteScore - Q2 (Control and Systems

Engineering)

Contact Us